

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

2611

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,793,822	08-1998	Anderson et al.	375/371
*	B	US-5,787,114	07-1998	Ramamurthy et al.	375/221
*	C	US-2004/0076119	04-2004	Aronson et al.	370/249
*	D	US-6,816,987	11-2004	Olson et al.	714/704
*	E	US-6,885,209	04-2005	Mak et al.	324/763
*	F	US-2002/0097682	07-2002	Enam et al.	370/241
*	G	US-5,675,584	10-1997	Jeong, Deog-Kyo	370/284
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

(Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

	U	Takahiro Yamaguchi, Mani Soma, Masahiro Ishida, Hirobumi Musha and Louis Malarsie, "A new method for testing Jitter tolerance of SerDes devices using sinusoidal jitter", Advantest Laboratories, University of Washington, Advantest Corporation, Agere Systems, ITC International Test Conference, 2002 IEEE).
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.